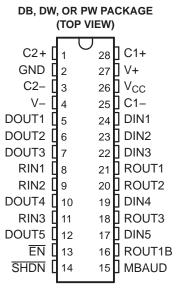
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3-V TO 5.5-V MULTICHANNEL RS-232 1-MBit/s LINE DRIVER/RECEIVER

Check for Samples: MAX3237E

FEATURES

- Meets or Exceeds the Requirements of TIA/EIA-232-F and ITU v.28 Standards
- Operates With 3-V to 5.5-V V_{CC} Supply
- Operates From 250 kbits/s to 1 Mbit/s
- Low Standby Current . . . 1 μA Typical
- External Capacitors . . . 4 × 0.1 μF
- Accepts 5-V Logic Input With 3.3-V Supply
- Designed to Be Interchangeable With Maxim MAX3237E
- Latch-Up Performance Exceeds 100 mA Per JESD 78, Class II



- ESD Protection for RS-232 I/O Pins
 - ±15 kV Human-Body Model (HBM)
 - ±8 kV IEC61000-4-2, Contact Discharge
 - ±15 kV IEC61000-4-2, Air-Gap Discharge

APPLICATIONS

- Battery-Powered, Hand-Held, and Portable Equipment
- PDAs and Palmtop PCs
- Notebooks, Sub-Notebooks, and Laptops
- Digital Cameras
- Mobile Phones and Wireless Devices

QFN PACKAGE

(TOP VIEW) U U U U U U U U 32 31 30 29 28 27 26 25 DOUT1 C1-⊃1 24 ⊂ DOUT2 b 2 DIN1 23 ⊂ DOUT3 > 3 IN2 22 RIN1 DIN₃ **□** 4 21 🗆 ROUT1 RIN2 → 5 20 ⊂ **⊃** 6 DOUT4 ROUT2 19 ⊂ RIN3 $\supset 7$ DIN4 18 ⊂ **₽**8 ROUT3 NC 17 9 10 11 12 13 14 15 16 n n n n n n n n

DESCRIPTION

The MAX3237E consists of five line drivers, three line receivers, and a dual charge-pump circuit with ± 15 -kV ESD protection pin to pin (serial-port connection pins, including GND). The device meets the requirements of TIA/EIA-232-F and provides the electrical interface between an asynchronous communication controller and the serial-port connector. The charge pump and four small external capacitors allow operation from a single 3-V to 5.5-V supply. This device operates at data signaling rates of 250 kbit/s in normal operating mode (MBAUD = GND) and 1Mbit/s when MBAUD = V_{CC} . The driver output slew rate is a maximum of 30 V/ μ s.



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.



The MAX3237E transmitters are disabled and the outputs are forced into high-impedance state when the device is in shutdown mode (SHDN = GND) and the supply current falls to less than 1 μ A. Also, during shutdown, the onboard charge pump is disabled; V+ is lowered to V_{CC}, and V- is raised toward GND. Receiver outputs also can be placed in the high-impedance state by setting enable (EN) high. ROUT1B remains active all the time, regardless of the EN and SHDN condition.

The MAX3237EC is characterized for operation from 0°C to 70°C. The MAX3237EI is characterized for operation from –40°C to 85°C.

AVAILABLE OPTIONS(1)

T _A	PACKAGED DEVICES ⁽²⁾
	MAX3237ECDBR
0°C to 70°C	MAX3237ECPWR
0.0 10 10.0	MAX3237ECRHBR (QFN package)
	MAX3237ECDWR
	MAX3237EIDBR
4000 +- 0500	MAX3237EIPWR
–40°C to 85°C	MAX3237EIRHBR (QFN package)
	MAX3237EIDWR

- (1) For the most current package and ordering information, see the Package Option Addendum at the end of this document, or see the TI web site at www.ti.com.
- (2) Package drawings, thermal data, and symbolization are available at www.ti.com/packaging.

Table 1. FUNCTION TABLE

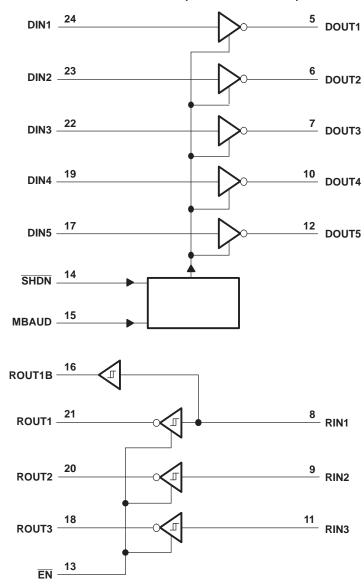
INPUT	S		OUTPUTS	
SHDN	EN	DOUT	ROUT	ROUT1B
0	0	Z ⁽¹⁾	Active	Active
0	1	Z ⁽¹⁾	Z ⁽¹⁾	Active
1	0	Active	Active	Active
1	1	Active	Z ⁽¹⁾	Active

(1) Z = high impedance (off)

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LOGIC DIAGRAM (POSITIVE LOGIC)





ABSOLUTE MAXIMUM RATINGS(1)

over operating free-air temperature range (unless otherwise noted)

			MIN	MAX	UNIT
V _{CC}	Supply voltage range (2)		-0.3	6	V
V+	Positive-output supply voltage range (2)	-0.3	7	V	
V-	Negative-output supply voltage range (2)		0.3	-7	V
V+ - V-	Supply voltage difference ⁽²⁾		13	V	
VI	land delta a serve	Driver (SHDN, MBAUD, EN)	-0.3	6	V
	Input voltage range	Receiver	-25	25	V
.,	Outrot valtana nama	Driver	-13.2	13.2	V
Vo	Output voltage range	Receiver	-0.3	$V_{CC} + 0.3$	V
	Short-circuit duration	DOUT to GND	Unlin	nited	
θ_{JA}	Package thermal impedance ⁽³⁾			62	°C/W
T _{stg}	Storage temperature range		-65	150	°C

⁽¹⁾ Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

RECOMMENDED OPERATING CONDITIONS(1)

See Figure 5

				MIN	NOM	MAX	UNIT
	Cumply yelfogo		V _{CC} = 3.3 V	3	3.3	3.6	V
	Supply voltage		V _{CC} = 5 V	4.5	5	5.5	V
.,	Deiver and control bink lavel innut valtage	DIN CUDN MRAUD EN	V _{CC} = 3.3 V	2		5.5	
V_{IH}	Driver and control high-level input voltage	DIN, SHDN, MBAUD, EN	V _{CC} = 5 V	2.4		5.5	V
V_{IL}	Driver and control low-level input voltage	DIN, SHDN, MBAUD, EN		0		0.8	V
VI	Receiver input voltage			-25		25	V
_	On another force six to see exclusive		MAX3237EC	0		70	9
T_A	Operating free-air temperature		MAX3237EI	-40		85	°C

⁽¹⁾ Test conditions are C1–C4 = 0.1 μ F at V_{CC} = 3 V to 5 V.

ELECTRICAL CHARACTERISTICS(1)

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (see Figure 5)

	PARAME	TER	TEST CONDITIONS	MIN TYP(2)	MAX	UNIT
I _I	Input leakage current	DIN, SHDN, MBAUD, EN		9	18	μА
			No load, SHDN = V _{CC}	0.5	2	mA
loo	Supply current		SHDN = GND	1	10	μΑ
Icc	$(T_A = 25^\circC)$	Shutdown supply current	SHDN = RIN = GND, DIN = GND or V _{CC}	10	300	nA

⁽¹⁾ Test conditions are C1–C4 = 0.1 μ F at V_{CC} = 3 V to 5 V.

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⁽²⁾ All voltages are with respect to network GND.

⁽³⁾ The package thermal impedance is calculated in accordance with JESD 51-7.

⁽²⁾ All typical values are at $V_{CC} = 3.3 \text{ V}$ or $V_{CC} = 5 \text{ V}$, and $T_A = 25 ^{\circ}\text{C}$.

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DRIVER SECTION ELECTRICAL CHARACTERISTICS(1)

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (see Figure 5)

	PARAMETER	TEST CONDITIONS			TYP ⁽²⁾	MAX	UNIT
V_{OH}	High-level output voltage	DOUT at $R_L = 3 \text{ k}\Omega$ to GND,	DIN = GND	5	5.4		V
V _{OL}	Low-level output voltage	DOUT at $R_L = 3 \text{ k}\Omega$ to GND,	DIN = V _{CC}	-5	-5.4		V
I _{IH}	High-level input current	$V_I = V_{CC}$			±0.01	±1	μΑ
I _{IL}	Low-level input current	V _I at GND			±0.01	±1	μΑ
Ios	Short-circuit output current ⁽³⁾	V _{CC} = 3.6 V or 3.3 V,	V _O = 0 V			±60	mA
ro	Output resistance	V_{CC} , V+, and V- = 0 V,	$V_0 = \pm 2 V$	300	50k		Ω

DRIVER SECTION SWITCHING CHARACTERISTICS(1)

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (see Figure 5)

		117		<u> </u>		, (
I	PARAMETER		TEST CONDITIONS		MIN	TYP ⁽²⁾	MAX	UNIT
Maximum data rate		C _L = 1000 pF, MBAUD = GND			250			
		C_L = 1000 pF, V_{CC} = 4.5 V to 5.5 V, MBAUD = V_{CC}	$R_L = 3 \text{ k}\Omega$, 1 DIN switching, See Figure 1	. ,				kbit/s
		C_L = 250 pF, V_{CC} = 3 V to 4.5 V, MBAUD = V_{CC}		1000				
t _{sk(p)}	Pulse skew ⁽³⁾	C_L = 150 pF to 2500 pF, f MBAUD = V_{CC} or GND, S				100		ns
	Slew rate, transition region (see Figure 1)	V _{CC} = 3.3 V,	$C_1 = 150 \text{ pF to } 1000 \text{ pF}$	MBAUD = GND	6		30	
SR(tr)		$R_L = 3 k\Omega$ to $7 k\Omega$,	CL = 130 pr to 1000 pr	$MBAUD = V_{CC}$	24		150	V/μs
		(see Figure 1) $T_A = 25^{\circ}C$		$C_L = 150 \text{ pF to } 2500 \text{ pF},$	MBAUD = GND	4		30

 ⁽¹⁾ Test conditions are C1–C4 = 0.1 μF at V_{CC} = 3 V to 5 V.
 (2) All typical values are at V_{CC} = 3.3 V or V_{CC} = 5 V, and T_A = 25°C.
 (3) Short-circuit durations should be controlled to prevent exceeding the device absolute power-dissipation ratings, and not more than one output should be shorted at a time.

Test conditions are C1–C4 = 0.1 μ F at V_{CC} = 3 V to 5 V. All typical values are at V_{CC} = 3.3 V or V_{CC} = 5 V, and T_A = 25°C. Pulse skew is defined as $|t_{PLH}-t_{PHL}|$ of each channel of the same device.



RECEIVER SECTION ELECTRICAL CHARACTERISTICS(1)

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (see Figure 5)

	PARAMETER	TEST CONDITIONS	MIN	TYP ⁽²⁾	MAX	UNIT
V _{OH}	High-level output voltage	I _{OH} = -1 mA	V _{CC} - 0.6	V _{CC} – 0.1		V
V _{OL}	Low-level output voltage	I _{OL} = 1 mA			0.4	V
	Decision and an instant three held college	V _{CC} = 3.3 V		1.5	2.4	
V _{IT+}	Positive-going input threshold voltage	V _{CC} = 5 V		2	2.4	V
V		V _{CC} = 3.3 V	0.6	1.1		V
V_{IT-}	Negative-going input threshold voltage	$V_{CC} = 5 V$	0.8	1.5		V
V _{hys}	Input hysteresis (V _{IT+} – V _{IT-})			0.5		V
l _{oz}	Output leakage current	EN = V _{CC}		±0.05	±10	μΑ
r _i	Input resistance	$V_1 = \pm 3 \text{ V to } \pm 25 \text{ V}$	3	5	7	kΩ

RECEIVER SECTION SWITCHING CHARACTERISTICS(1)

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	TYP ⁽²⁾	UNIT
t _{PLH}	Propagation delay time, low- to high-level output	C _L = 150 pF, See Figure 3	150	ns
t _{PHL}	Propagation delay time, high- to low-level output	C _L = 150 pF, See Figure 3	150	ns
t _{en}	Output enable time	$C_L = 150 \text{ pF}, R_L = 3 \text{ k}\Omega, \text{ See Figure 4}$	2.6	μS
t _{dis}	Output disable time	$C_L = 150 \text{ pF}, R_L = 3 \text{ k}\Omega, \text{ See Figure 4}$	2.4	μS
t _{sk(p)}	Pulse skew ⁽³⁾	See Figure 3	50	ns

ESD PROTECTION

PIN	TEST CONDITIONS	TYP	UNIT
	НВМ	±15	
DOUT, RIN	IEC61000-4-2, Contact Discharge	±8	kV
	IEC61000-4-2, Air-Gap Discharge	±15	

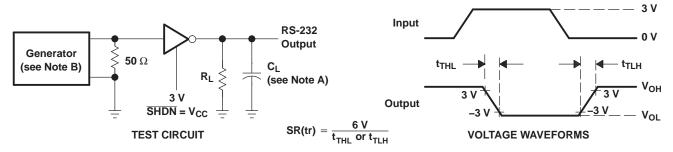
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⁽¹⁾ Test conditions are C1–C4 = 0.1 mF at V_{CC} = 3 V to.5 V. (2) All typical values are at V_{CC} = 3.3 V or V_{CC} = 5 V, and T_A = 25°C.

Test conditions are C1–C4 = 0.1 μ F at V_{CC} = 3 V to 5 V. All typical values are at V_{CC} = 3.3 V or V_{CC} = 5 V, and T_A = 25°C. Pulse skew is defined as $|t_{PLH}-t_{PHL}|$ of each channel of the same device.



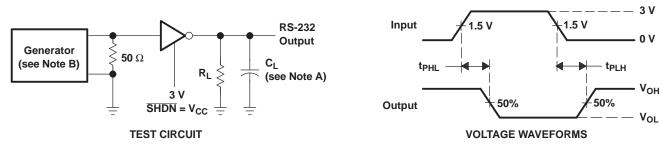
PARAMETER MEASUREMENT INFORMATION



NOTES: A. C_L includes probe and jig capacitance.

B. The pulse generator has the following characteristics: PRR = 250 kbit/s, $Z_O = 50~\Omega$, 50% duty cycle, $t_r \le 10$ ns. $t_f \le 10$ ns.

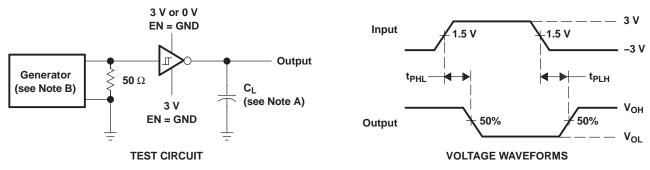
Figure 1. Driver Slew Rate



NOTES: A. C_L includes probe and jig capacitance.

B. The pulse generator has the following characteristics: PRR = 250 kbit/s, $Z_O = 50 \Omega$, 50% duty cycle, $t_r \le 10$ ns. $t_f \le 10$ ns.

Figure 2. Driver Pulse Skew



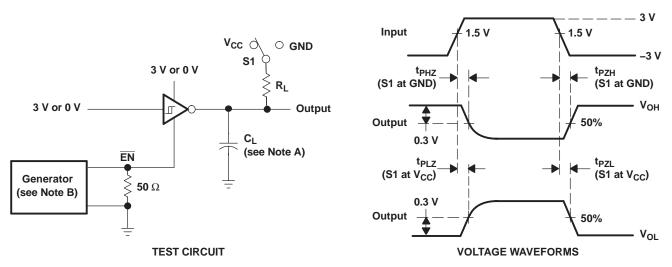
NOTES: A. C_L includes probe and jig capacitance.

B. The pulse generator has the following characteristics: $Z_0 = 50 \ \Omega$, 50% duty cycle, $t_r \le 10$ ns. $t_f \le 10$ ns.

Figure 3. Receiver Propagation Delay Times



PARAMETER MEASUREMENT INFORMATION (continued)



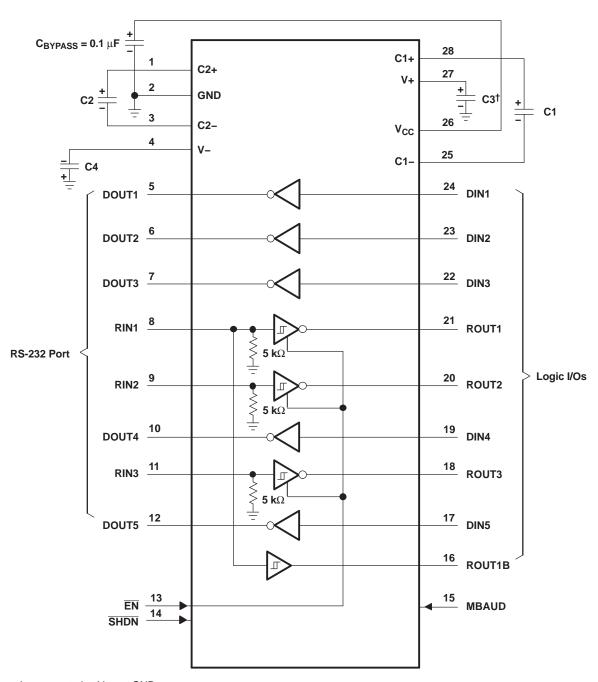
NOTES: A. C_L includes probe and jig capacitance.

- B. The pulse generator has the following characteristics: $Z_O = 50~\Omega$, 50% duty cycle, $t_r \le 10~ns$, $t_f \le 10~ns$.
- C. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
- D. t_{PZL} and t_{PZH} are the same as t_{en}.

Figure 4. Receiver Enable and Disable Times



APPLICATION INFORMATION



 $^{^{\}dagger}$ C3 can be connected to $V_{\mbox{\footnotesize CC}}$ or GND.

NOTES: A. Resistor values shown are nominal.

B. Nonpolarized ceramic capacitors are acceptable. If polarized tantalum or electrolytic capacitors are used, they should be connected as shown.

V_{CC} vs CAPACITOR VALUES

V _{CC}	C1	C2, C3, and C4
$\begin{array}{c} 3.3 \text{ V} \pm 0.15 \text{ V} \\ 3.3 \text{ V} \pm 0.3 \text{ V} \\ 5 \text{ V} \pm 0.5 \text{ V} \\ 3 \text{ V to } 5.5 \text{ V} \end{array}$	0.1 μF 0.22 μF 0.047 μF 0.22 μF	0.1 μF 0.22 μF 0.33 μF 1 μF

Figure 5. Typical Operating Circuit and Capacitor Values



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PACKAGING INFORMATION

Orderable Device	Status	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead finish/ Ball material	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
MAX3237ECDB	NRND	SSOP	DB	28	50	RoHS & Green	(6) NIPDAU	Level-1-260C-UNLIM	0 to 70	MAX3237EC	
MAX3237ECDBR	ACTIVE	SSOP	DB	28	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	0 to 70	MAX3237EC	Samples
MAX3237ECDW	ACTIVE	SOIC	DW	28	20	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	0 to 70	MAX3237EC	Samples
MAX3237ECDWG4	ACTIVE	SOIC	DW	28	20	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	0 to 70	MAX3237EC	Samples
MAX3237ECDWR	ACTIVE	SOIC	DW	28	1000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	0 to 70	MAX3237EC	Samples
MAX3237ECPW	NRND	TSSOP	PW	28	50	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	0 to 70	MP237EC	
MAX3237ECPWR	NRND	TSSOP	PW	28	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	0 to 70	MP237EC	
MAX3237EIDB	NRND	SSOP	DB	28	50	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	MAX3237EI	
MAX3237EIDBR	ACTIVE	SSOP	DB	28	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	MAX3237EI	Samples
MAX3237EIDW	ACTIVE	SOIC	DW	28	20	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	MAX3237EI	Samples
MAX3237EIPW	NRND	TSSOP	PW	28	50	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	MP237EI	
MAX3237EIPWR	ACTIVE	TSSOP	PW	28	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	MP237EI	Samples

⁽¹⁾ The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

⁽²⁾ RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

⁽³⁾ MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.



PACKAGE OPTION ADDENDUM

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- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead finish/Ball material Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

PACKAGE MATERIALS INFORMATION

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TAPE AND REEL INFORMATION





A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
MAX3237ECDBR	SSOP	DB	28	2000	330.0	16.4	8.2	10.5	2.5	12.0	16.0	Q1
MAX3237ECDWR	SOIC	DW	28	1000	330.0	32.4	11.35	18.67	3.1	16.0	32.0	Q1
MAX3237ECPWR	TSSOP	PW	28	2000	330.0	16.4	6.9	10.2	1.8	12.0	16.0	Q1
MAX3237EIDBR	SSOP	DB	28	2000	330.0	16.4	8.2	10.5	2.5	12.0	16.0	Q1
MAX3237EIPWR	TSSOP	PW	28	2000	330.0	16.4	6.9	10.2	1.8	12.0	16.0	Q1



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*All dimensions are nominal

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Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
MAX3237ECDBR	SSOP	DB	28	2000	356.0	356.0	35.0
MAX3237ECDWR	SOIC	DW	28	1000	350.0	350.0	66.0
MAX3237ECPWR	TSSOP	PW	28	2000	356.0	356.0	35.0
MAX3237EIDBR	SSOP	DB	28	2000	356.0	356.0	35.0
MAX3237EIPWR	TSSOP	PW	28	2000	356.0	356.0	35.0

PACKAGE MATERIALS INFORMATION

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TUBE



*All dimensions are nominal

Device	Package Name	Package Type	Pins	SPQ	L (mm)	W (mm)	T (µm)	B (mm)
MAX3237ECDB	DB	SSOP	28	50	530	10.5	4000	4.1
MAX3237ECDW	DW	SOIC	28	20	506.98	12.7	4826	6.6
MAX3237ECDWG4	DW	SOIC	28	20	506.98	12.7	4826	6.6
MAX3237ECPW	PW	TSSOP	28	50	530	10.2	3600	3.5
MAX3237EIDB	DB	SSOP	28	50	530	10.5	4000	4.1
MAX3237EIDW	DW	SOIC	28	20	506.98	12.7	4826	6.6
MAX3237EIPW	PW	TSSOP	28	50	530	10.2	3600	3.5



SMALL OUTLINE PACKAGE



NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

 2. This drawing is subject to change without notice.

 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm per side.
- 5. Reference JEDEC registration MO-150.



SMALL OUTLINE PACKAGE



NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SMALL OUTLINE PACKAGE



NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.



DW (R-PDSO-G28)

PLASTIC SMALL OUTLINE



NOTES: A. All linear dimensions are in inches (millimeters). Dimensioning and tolerancing per ASME Y14.5M-1994.

- B. This drawing is subject to change without notice.
- C. Body dimensions do not include mold flash or protrusion not to exceed 0.006 (0,15).
- D. Falls within JEDEC MS-013 variation AE.



PW (R-PDSO-G28)

PLASTIC SMALL OUTLINE



NOTES:

- A. All linear dimensions are in millimeters. Dimensioning and tolerancing per ASME Y14.5M—1994.
- B. This drawing is subject to change without notice.
- Body length does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0,15 each side.
- Body width does not include interlead flash. Interlead flash shall not exceed 0,25 each side.
- E. Falls within JEDEC MO-153



PW (R-PDSO-G28)

PLASTIC SMALL OUTLINE



NOTES:

- All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
 C. Publication IPC-7351 is recommended for alternate design.
- D. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC-7525 for other stencil recommendations.
- E. Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.



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